# Semiconductor Data Analysis Software

yieldWerx is the perfect solution for Semiconductor Test Data Analysis engineers who want to monitor their semiconductor products throughout the manufacturing processes.

It provides test and product engineers with the data visibility needed for yield enhancement, product characterization, and improving time in releasing the product to the production and the market.

## Here are some of the major features that yieldWerx offers:

yieldWerx Database – Easily upload hundreds of STDF test data files from across Work Centers, Test Programs, Lots, and Wafers, and run reports that compare test results across Wafers and Lots. Simple Windows drill down capabilities allow you to maintain your Die and Wafer Genealogy.
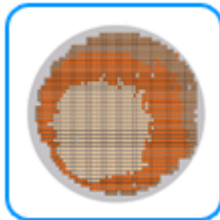
Parametric Wafer Map – You can generate wafer maps for test parameters and visually see the distribution of results by die location. The report can aggregate data from multiple wafers and stack them for cross wafer or lot analysis. The report can also be run for parametric zonal analysis simply by sorting results by wafer. [Applicable to only Wafer Probe Data]
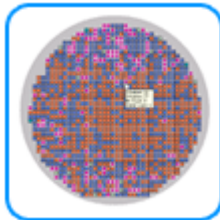
Stacked Wafer Map – This report is similar to the single wafer map report, however instead of showing the wafers as individual maps, the output is a stacked map representation of all the wafers for either Bins or Soft Bins. [Applicable to only Wafer Probe Data]
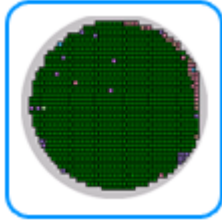
Wafer Map – This report visually generates a representation of a wafer showing either Bins or Soft Bins. The report can be run for multiple wafers and multiple lots. , The output of the reports can be aggregated by bin population/wafer yields by wafer, lot, or test program. [Applicable to only Wafer Probe Data]
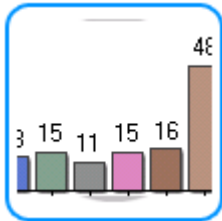

Parametric Histogram – Generates histograms for a given test parameter and represents the data as a series of classes. The report can aggregate data from multiple wafers and stack them for cross wafer or lot analysis. The report can be used for both Parametric as well as Functional test parameters. [Applicable to both Wafer Probe as well as Final Test Data]
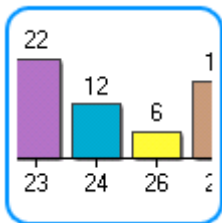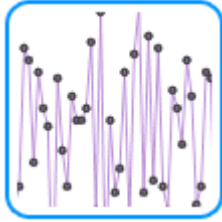

Bin Histogram – This report allows you to generate Bin summaries for both Wafer probe data as well as Final Test Data based on Bins, Soft Bins, as well as User Defined Bin Groups. The report shows you the yield for the selected data as well as other statistics as a series of bar charts. [Applicable to both Wafer Probe as well as Final Test Data]

Stacked Bin Histogram – This report allows you to generate Bin summaries for both Wafer probe data as well as Final Test Data based on Bins, Soft Bins, as well as User Defined Bin Groups. The report shows you the yield for the selected data as well as other statistics as a series of stacked histograms. [Applicable to both Wafer Probe as well as Final Test Data]
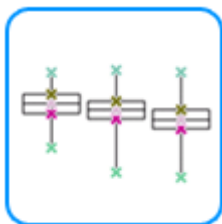
Box Plots – This report allows you to select two parameters and plot them against each other for as many wafers/lots as you select. The data plotted provides visualizations to see if there is any correlation between the two. [Applicable to both Wafer Probe as well as Final Test Data]

Parametric Trend – This report allows you to generate trend charts for either a single parameter or groups of parameters where the units of measurements are similar. Graphically allows you to visualize trends/relationships as well as other key statistics. [Applicable to both Wafer Probe as well as Final Test Data]

Data Reports:

Parametric Failure Report – A very simple report that shows you the top most failing tests based on limits included in the data source or user specified. Useful for showing you what tests are failing the most or the least and to take appropriate action. [Applicable to both Wafer Probe as well as Final Test Data]


Data Extraction: This report allows you to select any of the test data points stored in the yieldWerx database and then extract the data into a table which can then be exported to Excel for further manipulation and analysis. You can select as many parameters, wafers and lots as you want. [Applicable to both Wafer Probe as well as Final Test Data]

Data Summary: Statistically analyze the results for any test parameter, and view the Mean, Standard Deviation, Cp, Cpk, Yield, and other statistical results for selected test parameters, wafers and or lots. [Applicable to both Wafer Probe as well as Final Test Data]


XY Scatter – This report allows you to select two parameters and plot them against each other for as many wafers/lots as you select. The data plotted provides visualizations to see if there is any correlation between the two. Again users are allowed to select limits and apply filters as needed. [Applicable to both Wafer Probe as well as Final Test Data]
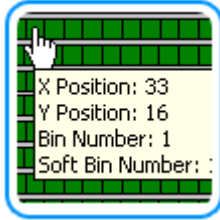
Smart Labels – Smart Data Labels allow for access to detailed data on the die plotted, without cluttering the graph too much.

Technology: yieldWerx is developed with Microsoft .Net Technology.
Database: Powered by Microsoft SQL Server Database
Export Reports to Microsoft Excel. You can export results to Microsoft Excel from any yieldWerx Report.
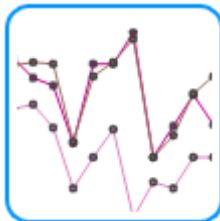
Interactive Charts – yieldWerx Interactive Reports allow you zoom in/out on reports, drill down into test parameter results for a die by clicking on the wafer map, and visually grouping the data by lot or wafer.